Testing the Purdue-3M Micromegas in the Cornell/Purdue TPC

Cornell University	Purdue University
D. P. PetersonL. FieldsR. S. GalikP. Onyisi	K. Arndt G. Bolla I. P. J. Shipsey

* presentation at ECFA 2005 Vienna
* presentation at ALCPG Snowmass
* presentation at LCWS05, Stanford
* presentation at TPC mini-workshop, Orsay
* presentation by Gino Bolla, Berkeley

24-November-2005 23-August-2005 21-March-2005 12-January-2005 March-2005

1

Information available at the web site: http://www.lepp.cornell.edu/~dpp/tpc_test_lab_info.html www.physics.purdue.edu/msgc

This project is supported by the US National Science Foundation (LEPP cooperative agreement) and by the US Department of Energy (Purdue HEP group base grant) and an LCRD/UCLC consortium grant



Purdue-3M Micromegas

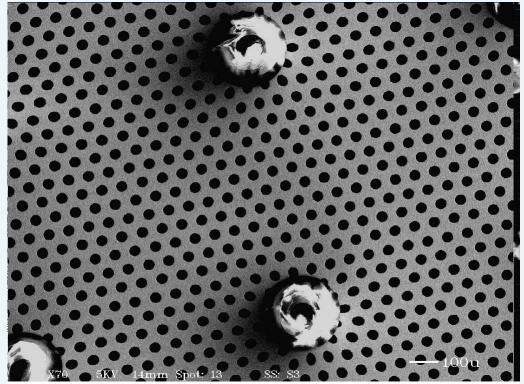
Micromegas is commercially made by the 3M corporation in a proprietary subtractive process starting with copper clad Kapton.

Hole are etched in the copper 70 µm spacing (smallest distance) 35 µm diameter

Copper thickness: $9 \ \mu m$?

Pillars are the remains of etched Kapton.
50 μm height
300 μm diameter at base
1 mm spacing, square array

The shiny surface of the pillars is due to charge build-up from the electron microscope.



Title: Copper Electrodes Comment: Kirk Arndt

Date: 03–22–2004 Time: 14:57 Filename: PHYSICS2.TIF



Purdue-3M Micromegas

Devices are delivered on a roll.

There are 2 designs,with and without the extra stand-off ribs.(The designs alternate on the roll.)

Active area is 6 cm square.

We are testing a device without ribs.

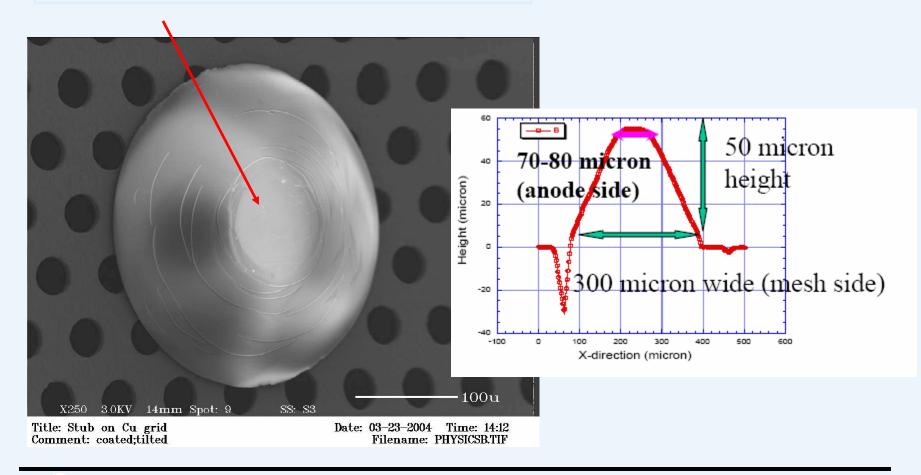


D. Peterson, "Testing a Purdue-3M Micromegas in the Cornell/Purdue TPC", TPC Applications Workshop, LBNL,07-04-2006

200

Purdue-3M Micromegas

High magnification photo shows the flat contact section of the pillar.



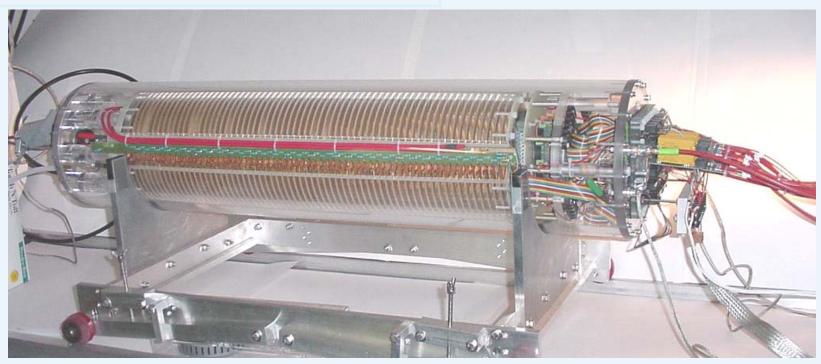


TPC

The construction is influenced by our research goal: to compare the various amplification technologies in a common environment.

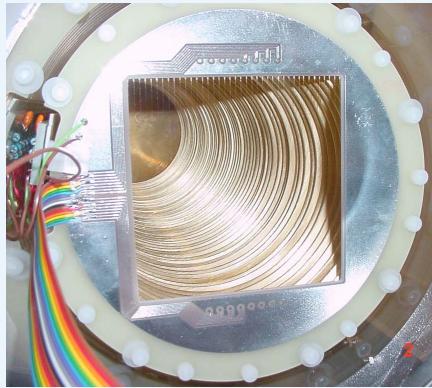
14.6 cm ID field cage - accommodates a 10 cm GEM64 cm drift field length22.2 cm OD outer structure (8.75 inch)

"field cage termination" and "final" return lines for the field cage HV distribution allow trimming the termination bias voltage. Read-out end: field cage termination **readout pad and amplification module** pad biasing boards CLEO II cathode preamps



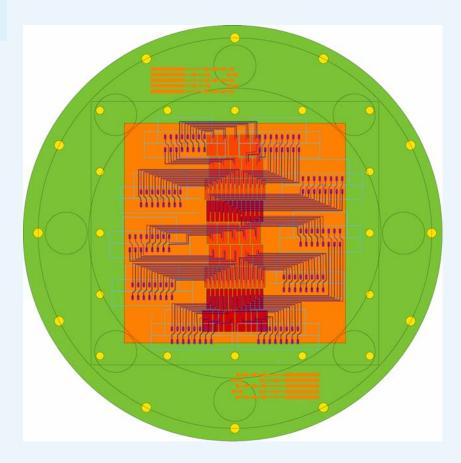


Field cage termination



10 cm

Field cage termination area is 10cm square



The instrumented readout area is ~2.5 cm x 9 cm , 80 pads. Instrument with only 56 channels The biased area is 10cm square.



Electronics

High voltage system:

-20 kV module, 2 channels available
-2 kV module, 4 channels available
+2 kV module, 4 channels (new)

previously used a NIM modules for +2kV

Readout:

VME crate PC interface card LabView

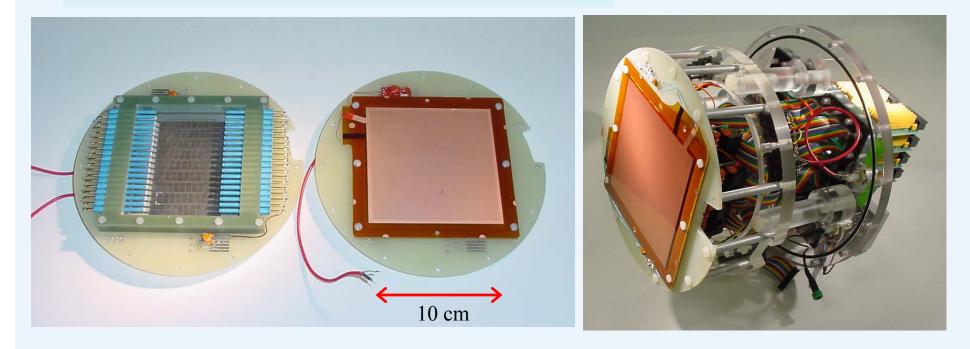
Struck FADC 56 channels 105 M Hz 14 bit +/- 200 mV input range (least count is 0.025mV) NIM external trigger input circular memory buffer







MPWC and GEM amplification



Demonstration data has been taken with the readout board with 5 mm width pads.

The instrumented readout area is $\sim 2 \text{ cm x7 cm}$, 32 pads.

The biased area is 10cm square.

(This pad board allows $\sim 3 \times 9 \text{ cm}$, 62 pads.)

The readout module including a double-GEM amplification device mounted on pad board



MWPC gas-amplification

MWPC built at Cornell with CLEO III drift chamber spare parts.

mounted Dec-2004

biasing: field cage, -20kV, 300 V/cm termination: -900V

termination:grid 300V/cm, 10mm

grid: -600V

grid:anode 5mm

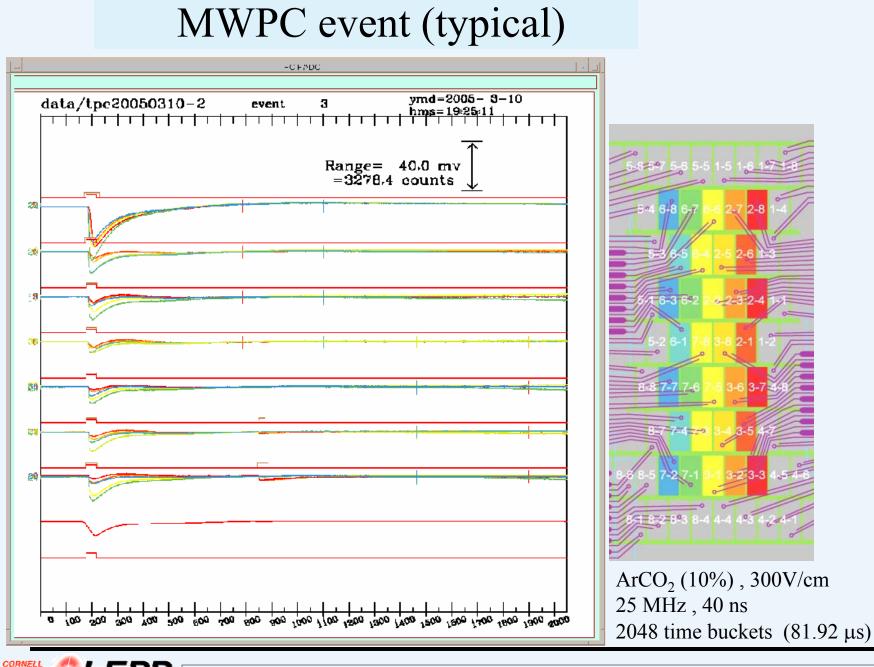
anode: +550V

anode:pads 5mm

pads: -2000V







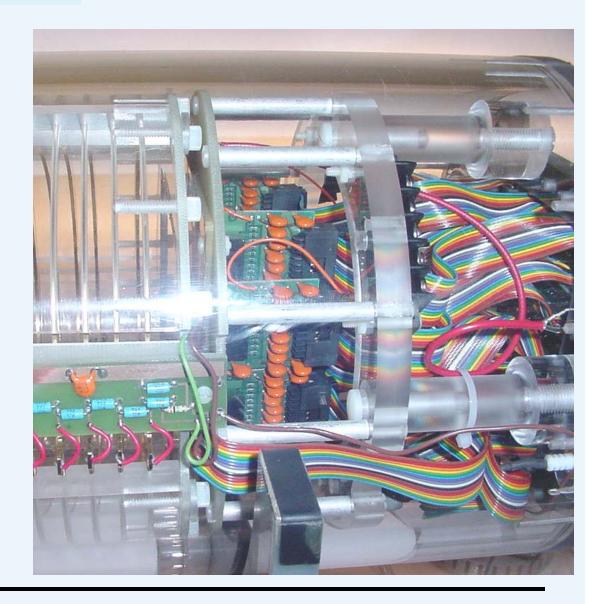


single GEM

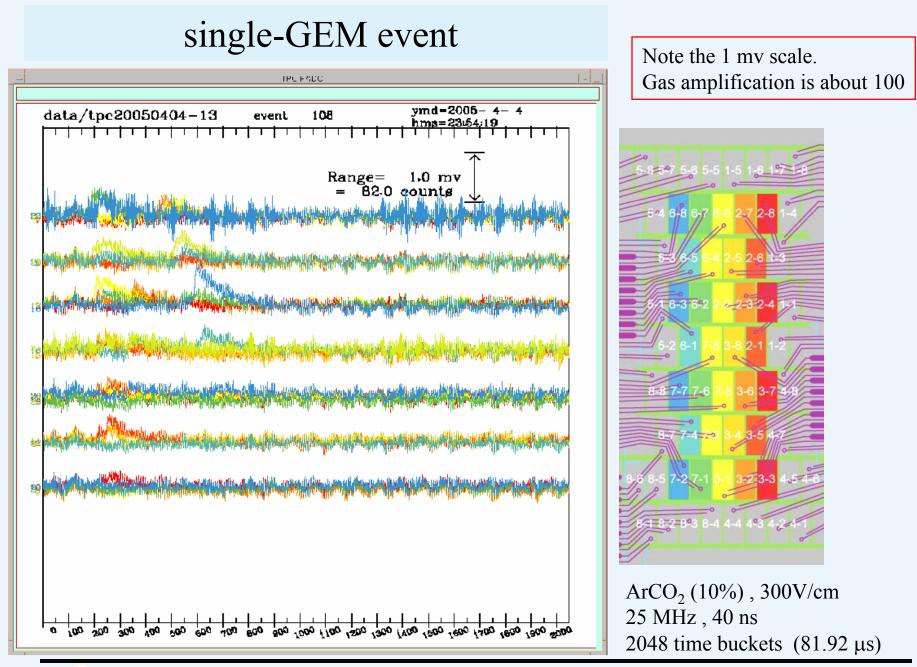
CERN GEM mounted, tested by Purdue installed 11-March-2005 biasing: field cage, -20kV, 300 V/cm termination: -900V termination : GEM **960V/cm**, 0.5 cm

GEM voltage: -400V , -400V:0V (Gas amplification ~100.) GEM : pads: **5000V/cm** , 0.3 cm,

pads: +1500 V

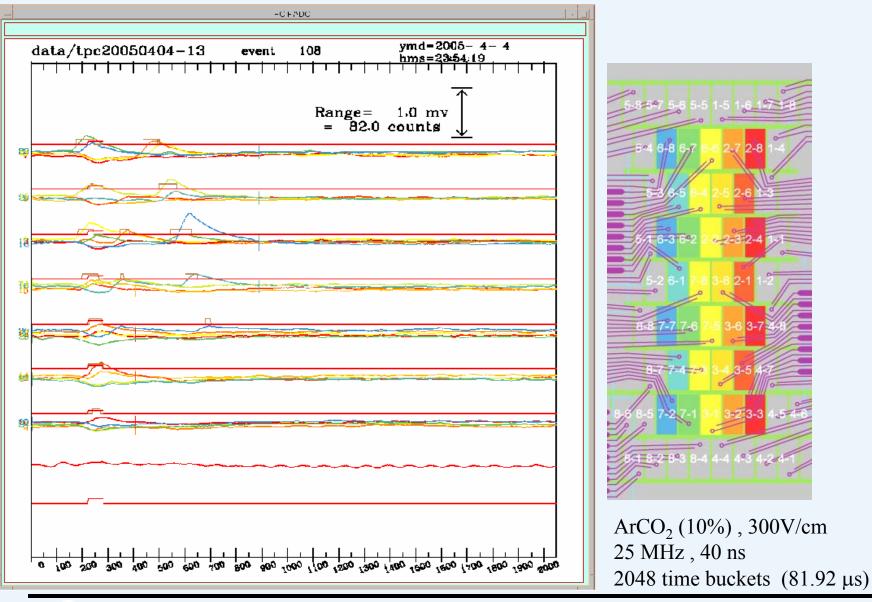








single-GEM after smoothing & common noise subtraction





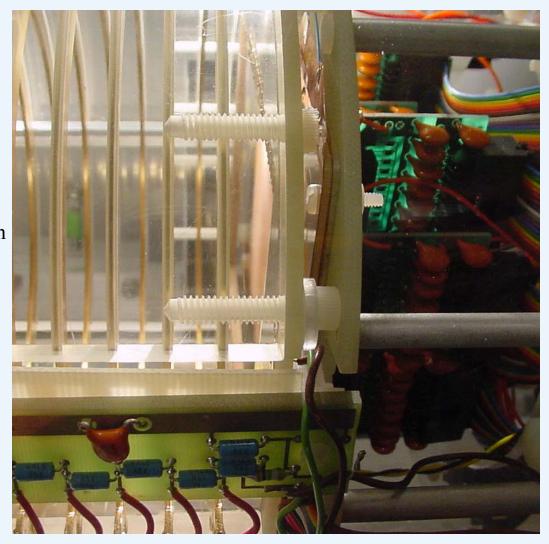
double-GEM

CERN GEM mounted, tested by Purdue

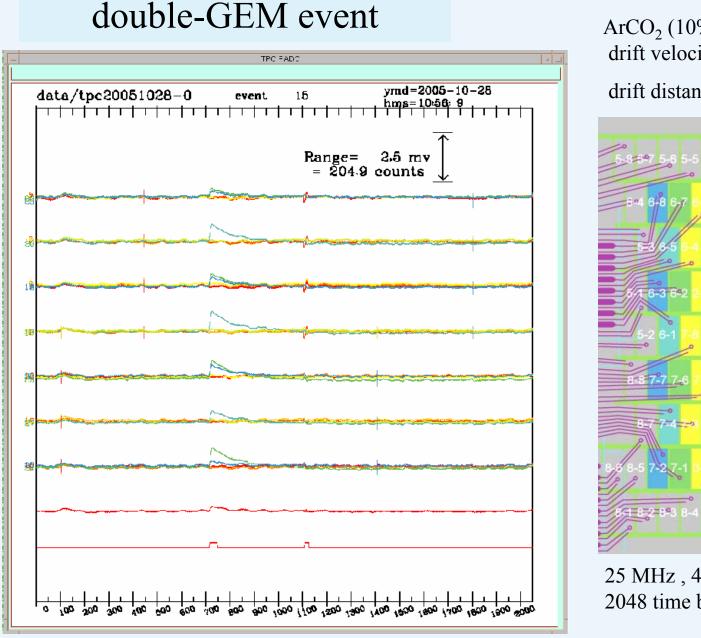
installed 20-October-2005

biasing: field cage, -20kV, 300 V/cm termination: -919V

termination : GEM2 **300V/cm** , 0.432 cm **GEM2 voltage: -370V** , -789V:-419V GEM2:GEM1 300V/cm , .165cm **GEM1 voltage: -370V** , -370V: 0 GEM1: pads **5000V/cm** , .165cm **pads: +825 V**

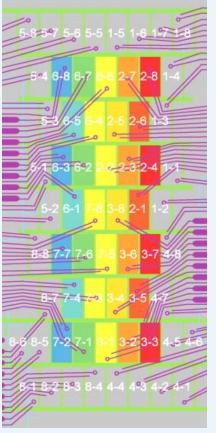






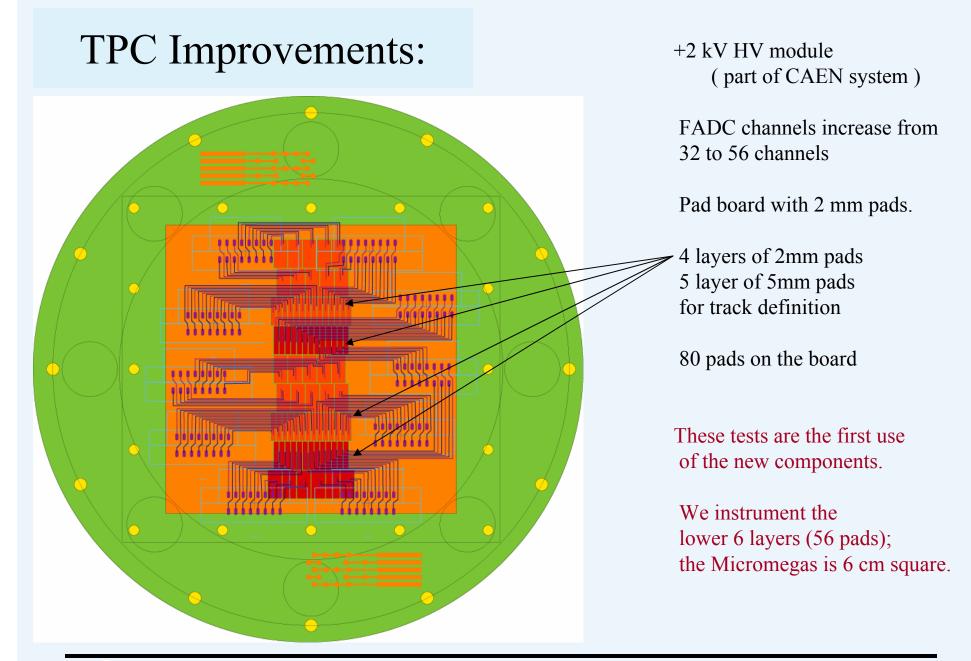
ArCO₂ (10%) , 300V/cm drift velocity = 22 μ m/ns

drift distance (this event) ~55cm



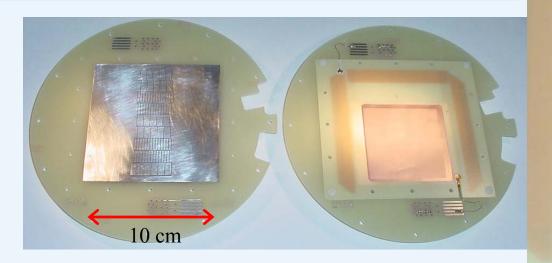
25 MHz , 40 ns 2048 time buckets (81.92 μs)







Micromegas amplification



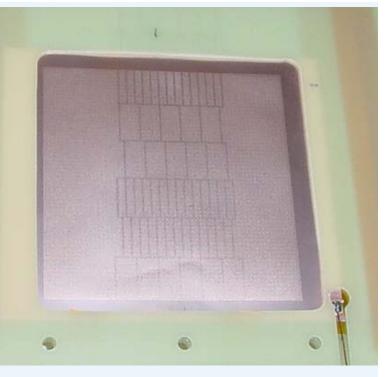
Plastic frame holds the Micromegas until electrostatic force pulls it in at about 250V.

The wrinkle flattens at about 400V.

56 pad readout

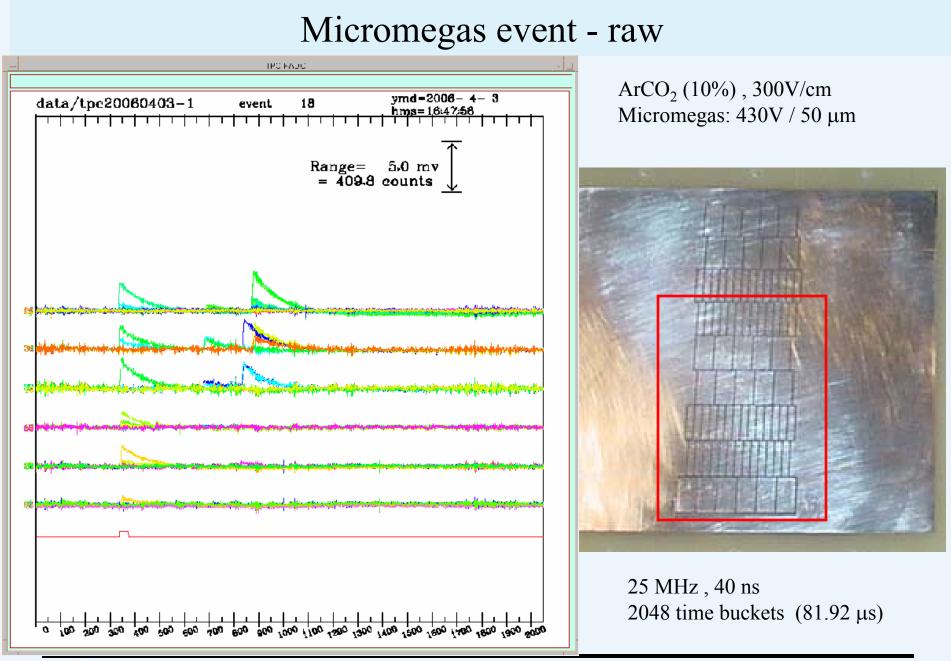
Pillars are located in a 1mm square array. All pads are located at integer x 1mm spacing.

The single 2mm pad layer (at top) is used to define the track angle, and thus, the residual difference of the pair of layers.



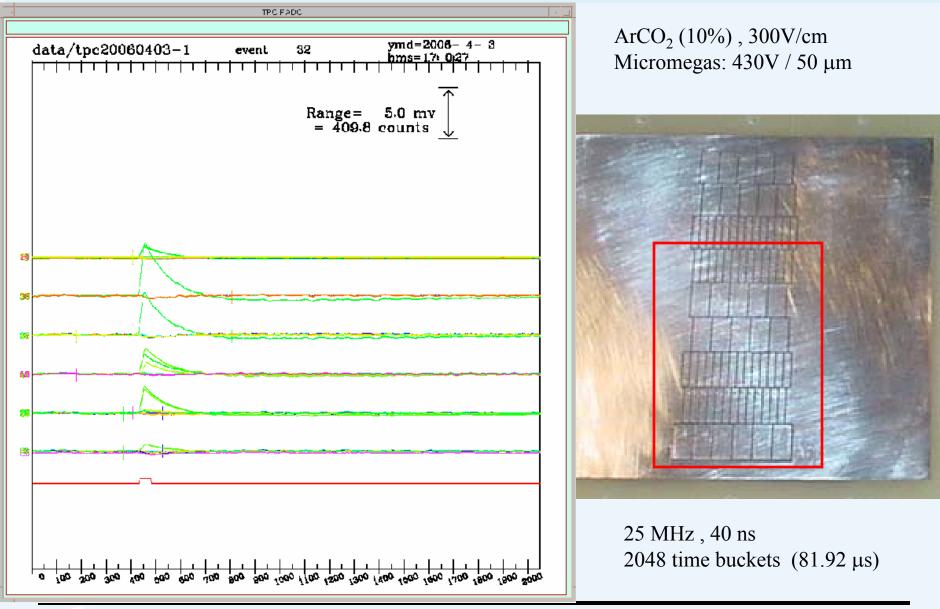




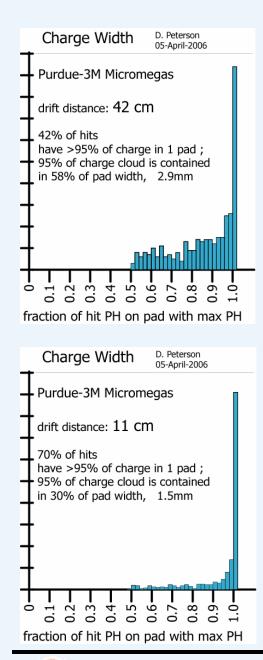




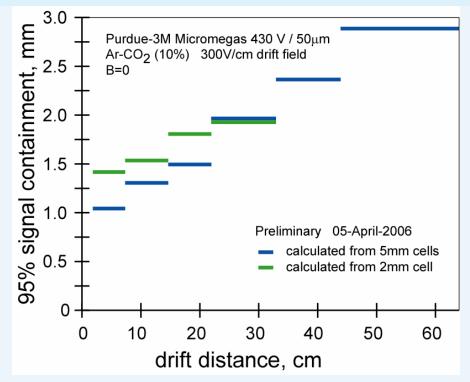
Micromegas event – smoothed (but no common mode subtraction)







charge width – pad distribution



As the charge width is less than the pad width, particularly in the 2 bins for drift < 14 cm, when charge is observed on adjacent pads, that charge is not centered on each on the pads.

The charge center on the pads must be corrected for an "effective pad width".





hit resolution (2mm pad)

find tracks

require time coincident signals in 5 layers

find PH center using maximum PH pad plus nearest neighbors (total 2 or 3 pads)

fit, deweighting the 5mm pad measurements

track selection

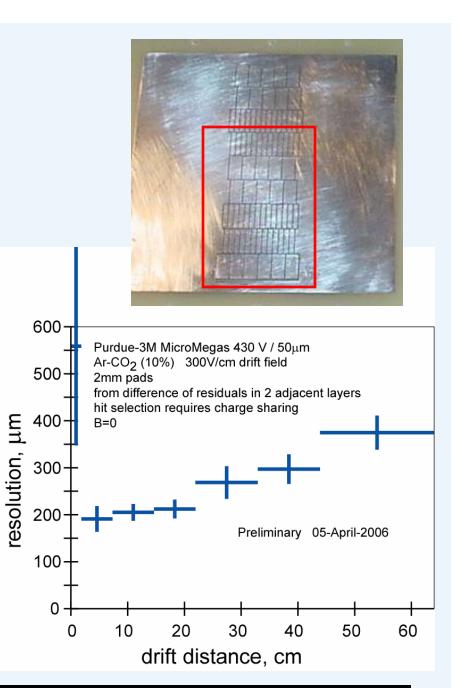
require all (3) 2mm pad layers "non-edge" hits in the adjacent 2mm layers charge sharing in the adjacent 2mm layers (< 95% of charge on one pad)

measure

RMS of difference in residual for the adjacent 2mm layers

correct with : $\sigma = RMS / \sqrt{2}$

with
$$C_d = .023/\sqrt{cm}$$
, N = 24





Sparking / Discharging

Ran for 10 days at 430 V in $ArCO_2$ (10%)

There was an initial training period to get from 400 V to 430 V, ~ 2 hours.

Sparks that tripped the HV occurred about 1 per 2 days after the first couple days.

The trip circuit was set at 40 μ A, for the minimum duration, less than 20 μ s.

(The last day of running was with a trip setting of 10 μ A for 0.2 sec – no trip.)

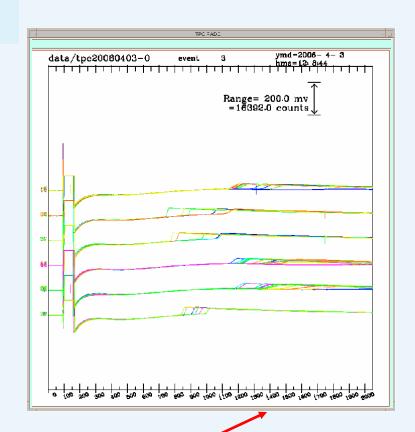
A new occurrence are the events as shown. (Note 200mv scale)

These could be due to the Micromegas.

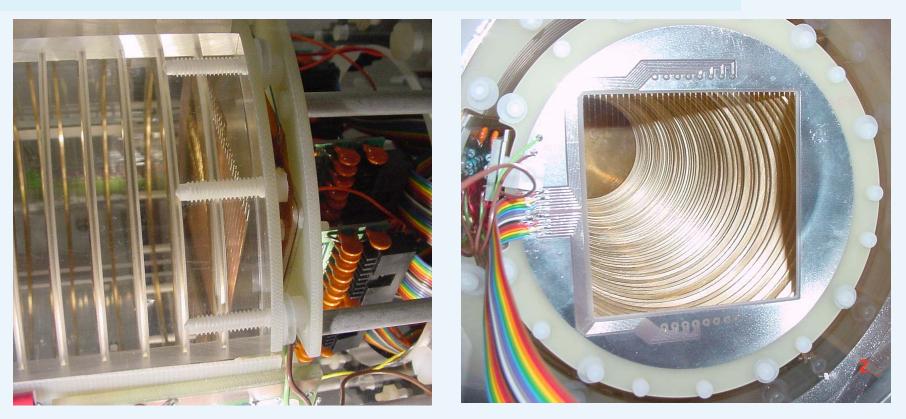
These could be an external problem.

They fake a scintillator trigger or are in-time with a scintillator trigger. More investigation...





Future: Ion Feedback Measurement



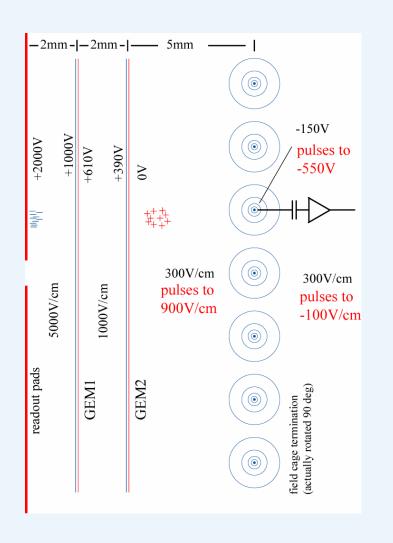
Positive ions are created in the amplification and drift back into the field cage.

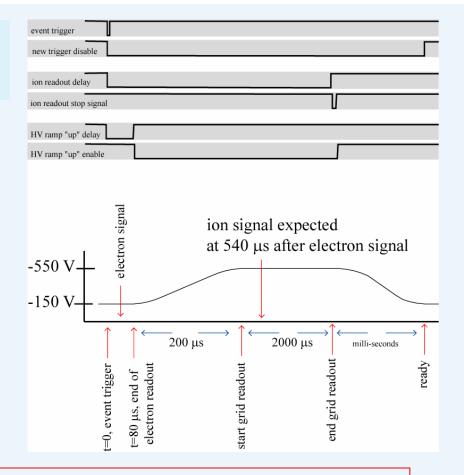
We will attempt to measure the ion feedback on the field cage termination plane, for individual tracks.

The method differs from that used by Saclay/Orsay on MicroMegas and by Aachen on GEM. For those measurements, a source was used to create ionization. Current was measured on the cathode.



Ion Feedback Measurement





Require small ion drift time to reduce diffusion. (Expect \sim 7 µs diffusion at 540 µs drift.)

Require large ion drift time because the amplifiers saturate during the voltage ramp. New amplifiers will have a recovery time within this drift time.



Summary / Outlook

We have operated the Purdue-3M Micromegas in a TPC.

The charge width (95% containment) is 1 to 1.4 mm at drift=0.

Resolution extrapolates to about 170 μ m with B=0.

Sparking/discharging is not a serious problem, but needs further investigation.

With the 2mm pad board, we are ready for comparative tests:

reinstall the double-GEM (CERN) (prepared by Purdue)

install a bulk Micromegas

install the resistive coating, for use with GEM or Micromegas

With a summer-program student for summer, 2006, we will make preliminary measurements for the ion-feedback studies.

